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INTERNATIONAL STANDARD

NORME INTERNATIONALE

AMENDMENT 1
AMENDEMENT 1

Semiconductor devices – Discrete devices – Part 5-5: Optoelectronic devices – Photocouplers

Dispositifs à semiconducteurs – Dispositifs discrets – Partie 5-5: Dispositifs optoélectroniques – Photocoupleurs

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FOREWORD

This amendment has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this amendment is based on the following documents:

CDV	Report on voting
47E/437/CDV	47E/451/RVC

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

5.2.7 Initial test voltage $V_{pd(ini)}$, V_{ini}

Delete the NOTE at the end of this subclause.

7.4.3

Delete the following text below the paragraph “Package construction”:

Periodic testing shall be carried out at the latest 5 years after type testing and shall be repeated at the latest every 5 years.

Delete the words “and periodic tests” *in the sentence “*Type tests and periodic tests shall include at least the following subgroups (7.4.3.1 to 7.4.3.8), with the following conditions:” *above the fourth dashed item.*

7.4.3.1 Preconditioning

Add, in the second paragraph, the terms “(IEC 60068-2-20, Test Tb, Method 1A)”, *as follows*:

Resistance to soldering heat	260 °C ± 5 °C, 5 s ± 1 s (IEC 60068-2-20, Test Tb, Method 1A)

7.4.3.2.1 Tests

Replace, in the paragraph “Vibration”*, the words* "Amplitude: 75 mm" *by* "Amplitude: 0,75 mm".

7.4.3.2.2 Final measurements

*Replace, in the paragraph “*Apparent charge”, "*F* = 1,6 or 1,2 (see 5.2.7 c)" *by* "*F* = 1,6 (see 5.2.7 c)".

7.4.3.3.2 Final measurements:

Replace, in the paragraph “Apparent charge”, "*F* = 1,2 or 1,0 (see 5.3.1 a); " *by* "*F* = 1,2 (see 5.2.7 c); ".

Table 2 – Tests and test sequence for photocoupler providing protection against electrical shock

Replace the existing Table 2 by the following new Table 2: